When it is "mission critical" and failure is not an option, KEMET has the solution.

Electronic Components
KEMET
CHARGED.

Applications

- Flight surface controllers
- Sensors
- Avionics
- Weapons systems
- Engine controllers
- Radar, guidance & GPS

Features & Benefits

- Ceramic & tantalum dielectrics
- Space
- Qualified product listing (QPL)
- MIL-PRE
- Defense logistics agency (DLA)
- High reliability Alternative (HRA)

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Auto Grade*

HRA

MIL-PRF Space Grade

T591/T598/T599
Automotive Grade Polymer

KPS
MLCC's Stacked Chip Capacitors (AUTO)

U2J
CxxxxxxxxxJ
Automotive Grade Class I Dielectric

T540/T541/T543
Polymer for High Reliability Applications

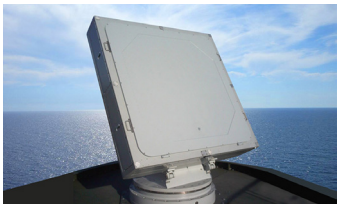
COTS
CxxxxT
High Reliability Applications
X7R/C0G Dielectric

PHS
T55*
Polymer for High Reliability Applications

T580/T581
Space Level Polymer
MIL-PRF in progress

Military
CxxxxK
High Reliability Applications
MIL-PRE 32535

Military
MLSS's for High Reliability Applications
MIL-PRF-49470



Ceramic COTS Test Levels

Test Level A	Test Level B	Test Level C
Voltage Conditioning, DWV, IR@85°C, CAPDF	Voltage Conditioning, DWV, IR@85°C, CAPDF	Voltage Conditioning, DWV, IR@85°C, CAPDF
PDA 8% Max Percent Defect Allowance	PDA 8% Max Percent Defect Allowance	PDA 8% Max Percent Defect Allowance
CofC Certificate of Compliance	DPA Per EIA-469	DPA Per EIA-469
	CofC Certificate of Compliance	LVH 85/85 per MIL-STD-202, Method 103, Cond. A
		CofC Certificate of Compliance

F-Tech Advantage

KEMET optional F-Tech eliminates hidden defects in the tantalum dielectric. This unique manufacturing process minimizes oxygen and carbon content in the anode, provides a stronger mechanical connection between anode and lead wire and significantly enhances capacitor robustness. F-Tech is available on select KEMET tantalum capacitor familes and can be conbined with SBDS.

Simulated Breakdown Screening (SBDS)

Breakdown voltage (BDV) is the ultimate test of a capacitor's robustness but is a destructive test. To simulate the results of a breakdown screening, KEMET developed a patented simulated Breakdown Screening (SBDS). This nondestructive testing technique simulated the BDV of a capacitor without damage to its dielectic. This 100% population screening identifies hidden defects in the dielectric, providing the highest level of dielectric testing.

SBDS is available on select KEMET tantalum capacitor families and can be combined with F-Tech.

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